

09/865,598.

L Number	Hits	Search Text	DB	Time stamp
1	4572	(707/3 707/100 707/200).ccls.	USPAT	2004/06/07 13:30
2	12986	707/\$.ccls.	USPAT	2004/06/07 13:30
4	1	invalid adj1 guess\$9	USPAT	2004/06/07 13:31
3	2	database adj1 block adj1 address\$2	USPAT	2004/06/07 13:34
5	74	guess\$9 same leaf	USPAT	2004/06/07 13:35
6	0	(guess\$9 same leaf) and ((707/3 707/100 707/200).ccls.)	USPAT	2004/06/07 13:36
7	10443	guess\$9	USPAT	2004/06/07 13:36
8	34177	split\$3 and index	USPAT	2004/06/07 13:37
9	24	(split\$3 and index ) and ((707/3 707/100 707/200).ccls.) and guess\$9	USPAT	2004/06/07 13:37
10	24	((split\$3 and index ) and ((707/3 707/100 707/200).ccls.) and guess\$9) and (ratio metadata address\$2 list block)	USPAT	2004/06/07 13:41

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